



Product/Process Change Notice - PCN 16_0136 Rev. -

Analog Devices, Inc. Three Technology Way Norwood, Massachusetts 02062-9106

This notice is to inform you of a change that will be made to certain ADI products (see Appendix A) that you may have purchased in the last 2 years. **Any inquiries or requests with this PCN (additional data or samples) must be sent to ADI within 30 days of publication date.** ADI contact information is listed below.

PCN Title: AD9572 Elimination of Cold Temp Test Screen
Publication Date: 04-Oct-2016
Effectivity Date: 21-Oct-2016 *(the earliest date that a customer could expect to receive changed material)*

Revision Description:

Initial Release

Description Of Change

ADI is eliminating cold temperature test screen @ -40 degrees C.

Reason For Change

ADI tested over 50k units from two different wafer lots and did not find any of the cold failures; a low voltage screen at room temperature has proven effective in its place.

Impact of the change (positive or negative) on fit, form, function & reliability

none

Product Identification *(this section will describe how to identify the changed material)*

1634

Summary of Supporting Information

Not applicable

Supporting Documents None

For questions on this PCN, please send an email to the regional contacts below or contact your local ADI sales representatives.

Americas: PCN_Americas@analog.com

Europe: PCN_Europe@analog.com

Japan: PCN_Japan@analog.com

Rest of Asia: PCN_ROA@analog.com

Appendix A - Affected ADI Models

Added Parts On This Revision - Product Family / Model Number (6)

AD9572 / AD9572ACPZLVD	AD9572 / AD9572ACPZLVD-R7	AD9572 / AD9572ACPZLVD-RL	AD9572 / AD9572ACPZPEC	AD9572 / AD9572ACPZPEC-R7
AD9572 / AD9572ACPZPEC-RL				

Appendix B - Revision History

Rev	Publish Date	Effectivity Date	Rev Description
Rev. -	04-Oct-2016	21-Oct-2016	Initial Release

Analog Devices, Inc.

DocId:3745 Parent DocId:None Layout Rev:7